
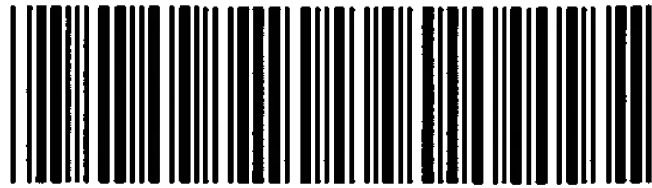


<b>Search Notes</b> 	<b>Application/Control No.</b>		<b>Applicant(s)/Patent under Reexamination</b>	
	09/751,429		REINSCHMIDT ET AL.	
	<b>Examiner</b>		<b>Art Unit</b>	
	Phallaka Kik		2825	

SEARCHED			
Class	Subclass	Date	Examiner
716	9,10,13,14	9/13/2005	PK
700	115,221	9/13/2005	PK
700	226	9/13/2005	PK
326	41,47,101	9/13/2005	PK
Above	Updated	2/22/2006	PK
Above	New	2/22/2006	PK
716	19,21	2/22/2006	PK
Above	updated	2/27/2006	PK
Above	new	2/27/2006	PK
257	758	2/27/2006	PK

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
716	9,10,13	2/27/2006	PK
716	14,19	2/27/2006	PK
700	115	2/27/2006	PK
257/758 --USPGPUB (see attached)		2/27/2006	PK

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
BRS (EAST) --USPAT, USPGPUB Cls/sub Searched: 716/1-21; 700/115-116,221-222,224-227, 326/38-50,101-103; 438/6-10 (see attach)	9/13/2005	PK
--EPO, JPO, IBM TDB, Derwent (see attached)	9/13/2005	PK
All above updated and new search (see attached)	2/22/2006	PK
Updated and new search: BRS (EAST) --USPAT, USGPUB Additional cls/sub searched: 257/758, e23.179 (see attached)	2/27/2006	PK
IEE/IEEE Xplore (see attached)	9/13/2005	PK
IEE/IEEE Xplore (see attached)	2/22/2006	PK
Consulted with Examiner Nathan W. Ha --case does not belong in 257 but may cross-ref. to 257/758	2/26/2006	PK
Consulted with Examiner Vibol Tan --no cross-ref. to 326; check with 257	2/24/2006	PK

**Search Notes (continued)**

Application/Control No.

09/751,429

Examiner

Phallaka Kik

Applicant(s)/Patent under  
Reexamination

REINSCHMIDT ET AL.

Art Unit

2825

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted with Examiner Sean Shechtman --suggested search in 700/115 and possible cross-referencing to 700/115	2/23/2006	PK
Consulted with Examiner Khoi Tran --does not belong in 700/213+. No cross-reference needed.	2/23/2006	PK